Examiner: Bryan Bui

2863

Art Unit:



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application of:

Soma et al.

Application No.: 10/665,970

Filed: September 18, 2003

For: CHARACTERIZATION OF RADIO FREQUENCY (RF) SIGNALS USING WAVELET-BASED PARAMETER

EXTRACTION

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Pursuant to 37 C.F.R. § 1.97, this Information Disclosure Statement is being submitted under one of the following (as indicated by an "X" to the left of the appropriate paragraph):

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	A sta	A statement pursuant to 37 C.F.R. §1.97(e) or					
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	(1)	A statement pursuant to 37 C.F.R. §1.97(e); and					
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If there are any additional charges, please charge Deposit Account No. 02-2666.

Respectfully submitted,

BLAKELY, SOKOLOFF, TAYLOR & ZAFMAN LLP

Dated: 4/19/2006

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Examiner Initials*	Cite No.1	Document Number Number-Kind Code ² (If known)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
	1	US-	6,295,315 B1	09-25-2001	Frisch et al.	
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FOREIGN PATENT DOCUMENTS						
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Substitute for Form 1449/PTO INFORMATION DISCLOSURE					Complete if Known		
					Application Number	10/665,970	
					Filing Date	September 18, 2003	
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					Examiner Name	Bryan Bui	
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				NON PATENT LIT	ERATURE DOCUMENTS		
Examiner Initials*	Cite No ¹			magazine, journal, se	AL LETTERS), title of the article (rial, symposium, catalog, etc.), da isher, city and/or country where p	te, page(s), volume-issue	T²
	2		BOUWMAN, F. et al., "Application of Joint Time-Frequency Analysis in Mixed Signal Testing," Proc. IEEE International Test Conference, pp. 747-756, Washington, DC, 1994.				
	3		YAMAGUCHI, T.J. et al., "Dynamic Testing of ADCs Using Wavelet Transforms," Proc. IEEE International Test Conference, pp. 379-388, Washington, DC, 1997.				
	4	SUNTER, S. et al., "BIST for Phase-Locked Loops in Digital Applications," Proc. IEEE International Test Conference, pp. 532-540, Sept. 28-30, 1999, Atlantic City, NJ.					
	5	MASON, R. et al., "Mixed Signal DFT at GHz Frequencies," J. of Electronic Testing: Theory and Applications 15, pp. 31-39, 1999.					
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	9	BHUNIA, S. et al., "Dynamic Supply Current Testing of Analog Circuits Using Wavelet Transform," Proc. IEEE VLSI Test Symposium, pp. 302-307, Monterey, CA, 2002.					
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